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### features

- 10-Bit Voltage Output DAC
- Programmable Settling Time vs Power Consumption
  - 3  $\mu$ s in Fast Mode 9  $\mu$ s in Slow Mode
- Ultra Low Power Consumption: 900 μW Typ in Slow Mode at 3 V 2.1 mW Typ in Fast Mode at 3 V
- Differential Nonlinearity . . . < 0.2 LSB Typ
- Compatible With TMS320 and SPI Serial Ports
- Power-Down Mode (10 nA)

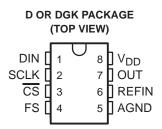
### description

The TLV5606 is a 10-bit voltage output digital-toanalog converter (DAC) with a flexible 4-wire serial interface. The 4-wire serial interface allows glueless interface to TMS320, SPI, QSPI, and Microwire serial ports. The TLV5606 is programmed with a 16-bit serial string containing 4 control and 10 data bits. Developed for a wide range of supply voltages, the TLV5606 can operate from 2.7 V to 5.5 V.

- Buffered High-Impedance Reference Input
- Voltage Output Range ... 2 Times the Reference Input Voltage
- Monotonic Over Temperature
- Available in MSOP Package

### applications

- Digital Servo Control Loops
- Digital Offset and Gain Adjustment
- Industrial Process Control
- Machine and Motion Control Devices
- Mass Storage Devices



The resistor string output voltage is buffered by a x2 gain rail-to-rail output buffer. The buffer features a Class AB output stage to improve stability and reduce settling time. The settling time of the DAC is programmable to allow the designer to optimize speed versus power dissipation. The settling time is chosen by the control bits within the 16-bit serial input string. A high-impedance buffer is integrated on the REFIN terminal to reduce the need for a low source impedance drive to the terminal.

Implemented with a CMOS process, the TLV5606 is designed for single supply operation from 2.7 V to 5.5 V. The device is available in an 8-terminal SOIC package. The TLV5606C is characterized for operation from 0°C to 70°C. The TLV5606I is characterized for operation from  $-40^{\circ}$ C to 85°C.

AVAILABLE OPTIONS									
	PACKAGE								
Τ <sub>Α</sub>	SMALL OUTLINE <sup>†</sup> (D)	MSOP <sup>†</sup> (DGK)							
0°C to 70°C	TLV5606CD	TLV5606CDGK							
-40°C to 85°C	TLV5606ID	TLV5606IDGK							

<sup>†</sup> Available in tape and reel as the TLV5606CDR, TLV5606IDR, TLV5606CDGKR, and the TLV5606IDGKR



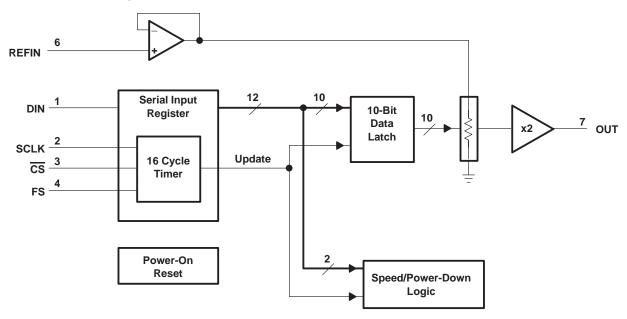
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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## functional block diagram



## **Terminal Functions**

TERMI	TERMINAL		
NAME	NO.	1/0	DESCRIPTION
AGND	5		Analog ground
CS	3	I	Chip select. Digital input used to enable and disable inputs, active low.
DIN	1	I	Serial digital data input
FS	4	Т	Frame sync. Digital input used for 4-wire serial interfaces such as the TMS320 DSP interface.
OUT	7	0	DAC analog output
REFIN	6	I	Reference analog input voltage
SCLK	2	I	Serial digital clock input
V <sub>DD</sub>	8		Positive power supply



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage (V <sub>DD</sub> to AGND)	
Reference input voltage range	
Digital input voltage range	– 0.3 V to V <sub>DD</sub> + 0.3 V
Operating free-air temperature range, T <sub>A</sub> : TLV5606C	0°C to 70°C
TLV5606I	–40°C to 85°C
Storage temperature range, T <sub>stg</sub>	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

		1	MIN	NOM	MAX	UNIT
	$V_{DD} = 5 V$		4.5	5	5.5	V
Supply voltage, V <sub>DD</sub>	$V_{DD} = 3 V$		2.7	3	3.3	V
Lligh lovel digital input valtage Mu	$DV_{DD} = 2.7 V$		2			V
High-level digital input voltage, VIH	DV <sub>DD</sub> = 5.5 V		2.4			V
Low level digital input voltage Ve	DV <sub>DD</sub> = 2.7 V				0.6	V
Low-level digital input voltage, $V_{IL}$	DV <sub>DD</sub> = 5.5 V				1	V
Reference voltage, Vref to REFIN terminal	$V_{DD} = 5 V$ (see Note 1)	AG	BND	2.048	V <sub>DD</sub> -1.5	V
Reference voltage, Vref to REFIN terminal	$V_{DD} = 3 V$ (see Note 1)	AG	BND	1.024	V <sub>DD</sub> -1.5	V
Load resistance, RL			2	10		kΩ
Load capacitance, CL					100	pF
Clock frequency, fCLK					20	MHz
	TLV5606C		0		70	°C
Operating free-air temperature, T <sub>A</sub>	TLV5606I		-40		85	°C

NOTE 1: Due to the x2 output buffer, a reference input voltage  $\ge V_{DD/2}$  causes clipping of the transfer function.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

#### power supply

	PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
		$V_{DD}$ = 5 V, VREF = 2.048 V, No load,	Fast		0.9	1.35	mA	
	Power supply current	All inputs = AGND or $V_{DD}$ , DAC latch = 0x800	Slow		0.4	0.6	mA	
DD			$V_{DD}$ = 3 V, VREF = 1.024 V No load,	Fast		0.7	1.1	mA
		All inputs = AGND or $V_{DD}$ , DAC latch = 0x800	Slow		0.3	0.45	mA	
	Power down supply current (see Figure	e 12)			10		nA	
PSRR	Power supply rejection ratio Zero scale Full scale		See Note 2		-80			dB
PORK			See Note 3		-80		uВ	
	Power on threshold voltage, POR				2		V	

NOTES: 2. Power supply rejection ratio at zero scale is measured by varying V<sub>DD</sub> and is given by:

 $PSRR = 20 \log [(E_{ZS}(V_{DD}max) - E_{ZS}(V_{DD}min))/V_{DD}max]$ 

3. Power supply rejection ratio at full scale is measured by varying  $V_{\mbox{DD}}$  and is given by:

PSRR = 20 log [(E<sub>G</sub>(V<sub>DD</sub>max) – E<sub>G</sub>(V<sub>DD</sub>min))/V<sub>DD</sub>max]



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### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted) (continued)

### static DAC specifications R<sub>L</sub> = 10 kΩ, C<sub>L</sub> = 100 pF

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Resolution			10	10	bits
INL	Integral nonlinearity	See Note 4		± 0.5	±1.5	LSB
DNL	Differential nonlinearity	See Note 5		± 0.2	± 1	LSB
EZS	Zero-scale error (offset error at zero scale)	See Note 6			±10	mV
	Zero-scale-error temperature coefficient	See Note 7		10		ppm/°C
EG	Gain error	See Note 8			±0.6	% of FS voltage
	Gain-error temperature coefficient	See Note 9		10		ppm/°C

NOTES: 4. The relative accuracy or integral nonlinearity (INL) sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors. Tested from code 10 to code 1023.

5. The differential nonlinearity (DNL) sometimes referred to as differential error, is the difference between the measured and ideal 1 LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code. Tested from code 10 to code 1023.

6. Zero-scale error is the deviation from zero voltage output when the digital input code is zero.

7. Zero-scale-error temperature coefficient is given by:  $E_{ZS} TC = [E_{ZS} (T_{max}) - E_{ZS} (T_{min})]/V_{ref} \times 10^6/(T_{max} - T_{min})$ . 8. Gain error is the deviation from the ideal output ( $2V_{ref} - 1 LSB$ ) with an output load of 10 k $\Omega$  excluding the effects of the zero-error. 9. Gain temperature coefficient is given by:  $E_G TC = [E_G(T_{max}) - E_G (T_{min})]/V_{ref} \times 10^6/(T_{max} - T_{min})$ .

#### output specifications

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VO	Voltage output range	$R_L = 10 \text{ k}\Omega$	0		AV <sub>DD</sub> -0.1	V
	Output load regulation accuracy	R <sub>L</sub> = 2 kΩ, vs 10 kΩ		0.1	±0.25	% of FS voltage

#### reference input (REF)

	PARAMETER	TEST CONDITIONS	TEST CONDITIONS				UNIT
VI	Input voltage range			0		V <sub>DD</sub> -1.5	V
RI	Input resistance						MΩ
Cl	Input capacitance						pF
			Slow		525		kHz
	Reference input bandwidth	REFIN = $0.2 V_{pp} + 1.024 V dc$	Fast		1.3		MHz
	Reference feed through	REFIN = 1 V <sub>pp</sub> at 1 kHz + 1.024 V c	REFIN = 1 V <sub>pp</sub> at 1 kHz + 1.024 V dc (see Note 10)				dB

NOTE 10: Reference feedthrough is measured at the DAC output with an input code = 0x000.

#### digital inputs

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Iн	High-level digital input current	$V_I = V_{DD}$			±1	μA
١L	Low-level digital input current	$V_{I} = 0 V$			±1	μA
Cl	Input capacitance			3		pF



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### operating characteristics over recommended operating free-air temperature range (unless otherwise noted)

## analog output dynamic performance

	PARAMETER	TEST	CONDITIONS		MIN	TYP	MAX	UNIT		
	Ordered a still and incention	R <sub>L</sub> = 10 kΩ,	С <sub>L</sub> = 100 рF,	Fast		3	5.5	_		
<sup>t</sup> s(FS)	Output settling time, full scale	See Note 11		Slow		9	20	μs		
		$R_L = 10 k\Omega$ ,	С <sub>L</sub> = 100 рF,	Fast		1		μs		
<sup>t</sup> s(CC)	Output settling time, code to code	See Note 12		Slow		2		μs		
SR	Olympicate	R <sub>L</sub> = 10 kΩ,	C <sub>L</sub> = 100 pF,	Fast		3.6		N// -		
SK	Slew rate	See Note 13	_	Slow	0.9			V/μs		
	Glitch energy	Code transition fr	om 0x7FF to 0x80	0		10		nV–s		
S/N	Signal to noise					62		dB		
S/(N+D)	Signal to noise + distortion		fs = 400  KSPS fout = 1.1 kHz,		,			60		dB
THD	Total harmonic distortion	$R_L = 10 k\Omega$ , $C_L = 100 pF$ , BW = 20 kHz				-61		dB		
	Spurious free dynamic range					68		dB		

NOTES: 11. Settling time is the time for the output signal to remain within ±0.5 LSB of the final measured value for a digital input code change of 0x080 to 0x3FF or 0x3FF to 0x080. Not tested, ensured by design.

12. Settling time is the time for the output signal to remain within ± 0.5 LSB of the final measured value for a digital input code change of one count. Code change from 0x1FF to 0x200. Not tested, ensured by design.

13. Slew rate determines the time it takes for a change of the DAC output from 10% to 90% full-scale voltage.

### digital input timing requirements

		MIN	NOM	MAX	UNIT
tsu(CS-FS)	Setup time, $\overline{\text{CS}}$ low before FS $\downarrow$	10			ns
<sup>t</sup> su(FS–CK)	Setup time, FS low before first negative SCLK edge	8			ns
<sup>t</sup> su(C16–FS)	Setup time, sixteenth negative edge after FS low on which bit D0 is sampled before rising edge of FS $$	10			ns
<sup>t</sup> su(C16–CS)	Setup time, sixteenth positive SCLK edge (first positive after D0 is sampled) before $\overline{CS}$ rising edge. If FS is used instead of the sixteenth positive edge to update the DAC, then the setup time is between the FS rising edge and $\overline{CS}$ rising edge.	10			ns
t <sub>wH</sub>	Pulse duration, SCLK high	25			ns
t <sub>wL</sub>	Pulse duration, SCLK low	25			ns
<sup>t</sup> su(D)	Setup time, data ready before SCLK falling edge	8			ns
<sup>t</sup> h(D)	Hold time, data held valid after SCLK falling edge	5			ns
<sup>t</sup> wH(FS)	Pulse duration, FS high	20			ns



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## PARAMETER MEASUREMENT INFORMATION

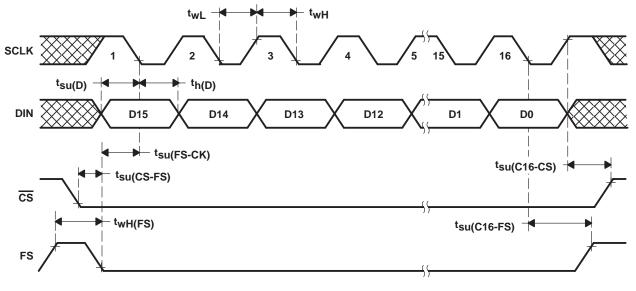
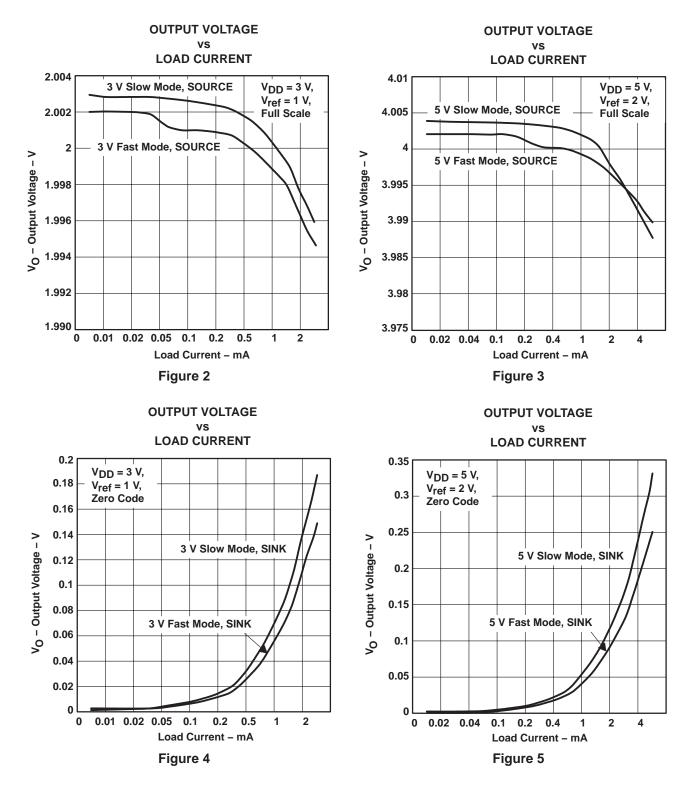


Figure 1. Timing Diagram



### TLV5606 2.7-V TO 5.5-V LOW POWER 10-BIT DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN SLAS259B – DECEMBER 1999 – REVISED APRIL 2004

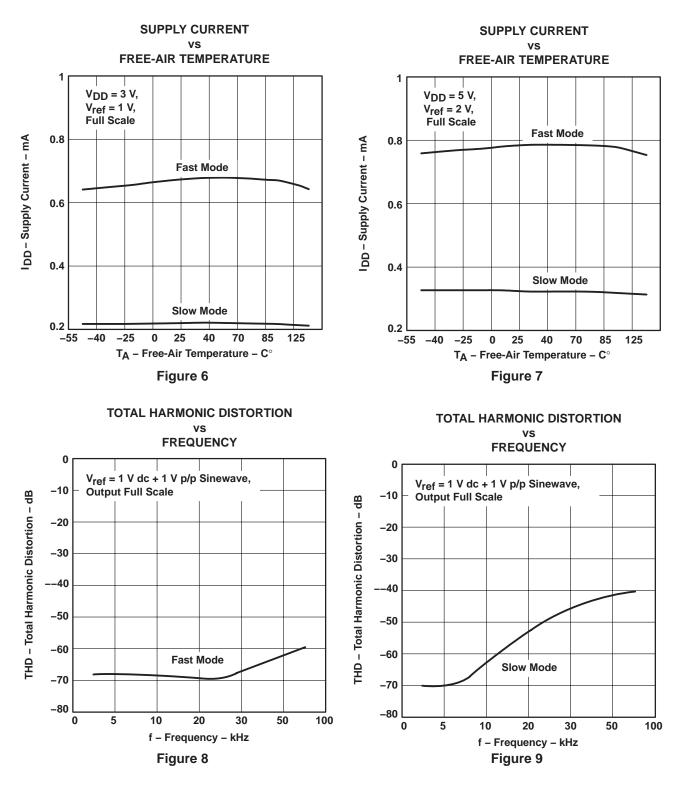
## **TYPICAL CHARACTERISTICS**





### TLV5606 2.7-V TO 5.5-V LOW POWER 10-BIT DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN SLAS259B – DECEMBER 1999 – REVISED APRIL 2004

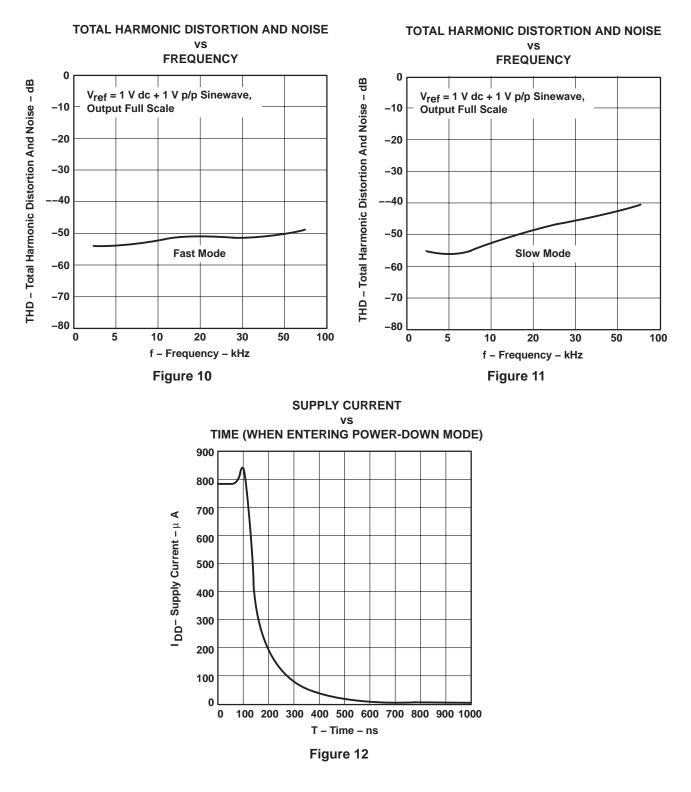
TYPICAL CHARACTERISTICS





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## **TYPICAL CHARACTERISTICS**

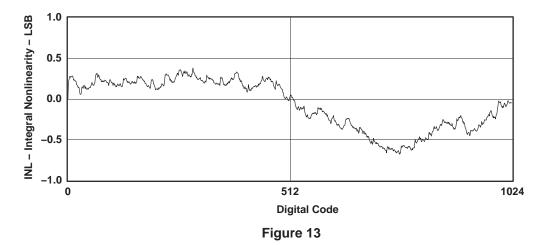




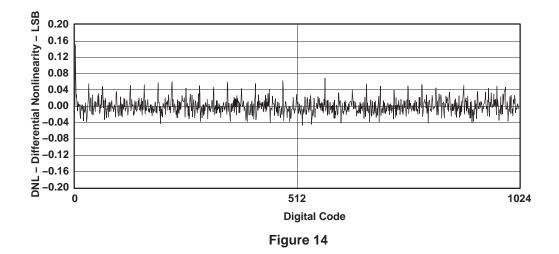
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## **TYPICAL CHARACTERISTICS**

### INTEGRAL NONLINEARITY ERROR









## APPLICATION INFORMATION

### general function

The TLV5606 is a 10-bit single supply DAC based on a resistor string architecture. The device consists of a serial interface, speed and power-down control logic, a reference input buffer, a resistor string, and a rail-to-rail output buffer.

The output voltage (full scale determined by external reference) is given by:

where REF is the reference voltage and CODE is the digital input value within the range of  $0_{10}$  to  $2^{n-1}$ , where n = 10 (bits). The 16-bit data word, consisting of control bits and the new DAC value, is illustrated in the *data format* section. A power-on reset initially resets the internal latches to a defined state (all bits zero).

### serial interface

Explanation of data transfer: First, the device has to be enabled with  $\overline{CS}$  set to low. Then, a falling edge of FS starts shifting the data bit-per-bit (starting with the MSB) to the internal register on the falling edges of SCLK. After 16 bits have been transferred or FS rises, the content of the shift register is moved to the DAC latch which updates the voltage output to the new level.

The serial interface of the TLV5606 can be used in two basic modes:

- Four wire (with chip select)
- Three wire (without chip select)

Using chip select (four wire mode), it is possible to have more than one device connected to the serial port of the data source (DSP or microcontroller). The interface is compatible with the TMS320 family. Figure 15 shows an example with two TLV5606s connected directly to a TMS320 DSP.

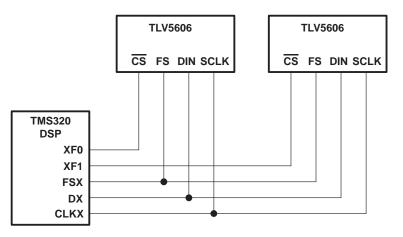


Figure 15. TMS320 Interface



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## **APPLICATION INFORMATION**

### serial interface (continued)

If there is no need to have more than one device on the serial bus, then  $\overline{CS}$  can be tied low. Figure 16 shows an example of how to connect the TLV5606 to a TMS320, SPI, or Microwire port using only three pins.

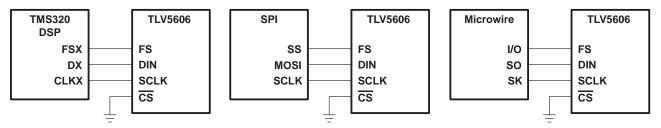


Figure 16. Three-Wire Interface

Notes on SPI and Microwire: Before the controller starts the data transfer, the software has to generate a falling edge on the I/O pin connected to FS. If the word width is 8 bits (SPI and Microwire), two write operations must be performed to program the TLV5606. After the write operation(s), the DAC output is updated automatically on the next positive clock edge following the sixteenth falling clock edge.

### serial clock frequency and update rate

The maximum serial clock frequency is given by:

$$f_{SCLKmax} = \frac{1}{t_{wH(min)} + t_{wL(min)}} = 20 \text{ MHz}$$

The maximum update rate is:

$$f_{UPDATEmax} = \frac{1}{16 \left(t_{wH(min)} + t_{wL(min)}\right)} = 1.25 \text{ MHz}$$

The maximum update rate is a theoretical value for the serial interface, since the settling time of the TLV5606 has to be considered also.

### data format

The 16-bit data word for the TLV5606 consists of two parts:

- Control bits (D15...D12)
- (D11 . . . D2) New DAC value

D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
Х	SPD	PWR	Х		New DAC value (10 bits)								0	0	

X: don't care

SPD: Speed control bit.  $1 \rightarrow \text{fast mode}$  $0 \rightarrow \text{slow mode}$ 

PWR: Power control bit.  $1 \rightarrow$  power down  $0 \rightarrow normal operation$ 

In power-down mode, all amplifiers within the TLV5606 are disabled.



## **APPLICATION INFORMATION**

### TLV5606 interfaced to TMS320C203 DSP

#### hardware interfacing

Figure 17 shows an example how to connect the TLV5606 to a TMS320C203 DSP. The serial interface of the TLV5606 is ideally suited to this configuration, using a maximum of four wires to make the necessary connections. In applications where only one synchronous serial peripheral is used, the interface can be simplified even further by pulling  $\overline{CS}$  low all the time as shown in the figure.

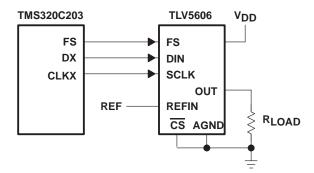


Figure 17. TLV5606 to DSP Interface

#### software

No setup procedure is needed to access the TLV5606. The output voltage can be set using just a single command.

out data\_addr, SDTR

where data\_addr points to an address location holding the control bits and the 12 data bits providing the output voltage data. SDTR is the address of the transmit FIFO of the synchronous serial port.

The following code shows how to use the timer of the TMS320C203 as a time base to generate a voltage ramp with the TLV5606.

A timer interrupt is generated every 205  $\mu$ s. The corresponding interrupt service routine increments the output code (stored at 0x0064) for the DAC, adds the DAC control bits to the four most significant bits, and writes the new code to the TLV5606. The resulting period of the saw waveform is:

 $\pi = 4096 \times 205 \text{ E-6 s} = 0.84 \text{ s}$ 

```
******
;* Title : Ramp generation with TLV5606
;* Version : 1.0
;* DSP
       : TI TMS320C203
;* © (1998) Texas Instruments Incorporated
;----- I/O and memory mapped regs ------
    .include "regs.asm"
 ----- vectors ------
                          _____
     .ps
           0h
     b
            start
     b
           INT1
     b
            INT23
     b
            TIM ISR
```



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**APPLICATION INFORMATION** 

```
;* Main Program
1000h
    .ps
    .entry
start:
; disable interrupts
                   ; disable maskable interrupts
    setc INTM
           #0ffffh, IFR
    splk
           #0004h, IMR
    splk
; set up the timer to interrupt ever 205uS
          #0000h, 60h
    splk
           #00FFh, 61h
    splk
    out
           61h, PRD
           60h, TIM
    out
          #0c2fh, 62h
    splk
           62h, TCR
    out
; Configure SSP to use internal clock, internal frame sync and burst mode
        #0CC0Eh, 63h
    splk
           63h, SSPCR
    out
           #0CC3Eh, 63h
    splk
           63h, SSPCR
    out
           #0000h, 64h ; set initial DAC value
    splk
; enable interrupts
           INTM
                   ; enable maskable interrupts
    clrc
; loop forever!
    idle
next:
                    ;wait for interrupt
      b
           next
; all else fails stop here
                    ; hang there
done: b done
;* Interrupt Service Routines
*****
INT1:
      ret
                    ;do nothing and return
INT23:
       ret
                    ;do nothing and return
TIM_ISR:
                   ; restore counter value to ACC
       lacl
           64h
                   ; increment DAC value
       add
           #4h
           #0FFCh
       and
                    ; mask 4 MSBs
                    ; store 12 bit counter value
       sacl 64h
                    ; set DAC control bits
           #4000h
       or
       sacl 65h
                    ; store DAC value
       out 65h, SDTR ; send data
                   ; re-enable interrupts
       clrc intm
       ret
.END
```



## **APPLICATION INFORMATION**

### TLV5606 interfaced to MCS51<sup>®</sup> microcontroller

#### hardware interfacing

Figure 18 shows an example of how to connect the TLV5606 to an MCS51<sup>®</sup> compatible microcontroller. The serial DAC input data and external control signals are sent via I/O port 3 of the controller. The serial data is sent on the RxD line, with the serial clock output on the TxD line. P3.4 and P3.5 are configured as outputs to provide the chip select and frame sync signals for the TLV5606.

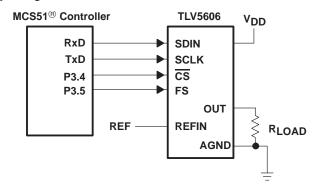


Figure 18. TLV5606 to MCS51<sup>®</sup> Controller Interface

#### software

The example program puts out a sine wave on the OUT pin.

The on-chip timer is used to generate interrupts at a fixed frequency. The related interrupt service routine fetches and writes the next sample to the DAC. The samples are stored in a lookup table, which describes one full period of a sine wave.

The serial port of the controller is used in mode 0, which transmits 8 bits of data on RxD, accompanied by a synchronous clock on TxD. Two writes concatenated together are required to write a complete word to the TLV5606. The CS and FS signals are provided in the required fashion through control of I/O port 3, which has bit addressable outputs.

```
*****
;* Title : Ramp generation with TLV5606
;* Version : 1.0
                                                                            *
;* MCU : INTEL MCS51<sup>®</sup>
;* © (1998) Texas Instruments Incorporated
; Program function declaration
;---
NAME
     GENSINE
MAIN
     SEGMENT
                 CODE
ISR
     SEGMENT
                 CODE
SINTBL SEGMENT
                 CODE
VAR1
     SEGMENT
                 DATA
STACK SEGMENT
                 IDATA
; Code start at address 0, jump to start
   ____
  CSEG AT 0
```

```
MCS is a registered trademark of Intel Corporation
```



## **TLV5606** 2.7-V TO 5.5-V LOW POWER 10-BIT DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN SLAS259B – DECEMBER 1999 – REVISED APRIL 2004

## **APPLICATION INFORMATION**

Code ir	n the timer0 interr	rupt vector
CSEG .		
		ump vector for timer 0 interrupt is 000Bh
Define	program variables	
RSEG	 VAR1	
5_1	ptr: DS 1	
: Interru	upt service routine	e for timer 0 interrupts
RSEG	ISR	
imer0is:	r:	
PUSH PUSH	PSW ACC	
CLR CLR	TO T1	; set CSB low ; set FS low
; hel ; rol	d in a table @ sind ling_ptr, rolls rou h interrupt (at the	ut on the dac is a sine function. One cycle of a sine wave is evals as 32 samples of msb, lsb pairs (64 bytes). The pointer und the table of samples incrementing by 2 bytes (1 sample) of e end of this routine). s ; set DPTR to the start of the table of sine signal values
MOV	A,rolling_ptr	; ACC loaded with the pointer into the sine table
MOVC ORL MOV	A,@A+DPTR A, #00H SBUF,A	; get msb from the table ; set control bits ; send out msb of data word
MOVA, INC MOVC	A	rolling pointer in to ACC ; increment ACC holding the rolling pointer ; which is the lsb of this sample, now in ACC
ASB_TX: JNB CLR MOV	TI, MSB_TX TI SBUF,A	; wait for transmit to complete ; clear for new transmit ; and send out the lsb
LSB_TX: JNB SETB CLR	TI, LSB_TX T1 TI	; wait for lsb transmit to complete ; set FS = 1 ; clear for new transmit
0 DIT	A,rolling ptr	; load ACC with rolling pointer ; increment the ACC twice, to get next sample
MOV INC INC ANL	A A A,#03FH	; wrap back round to 0 if $>64$
MOV INC INC ANL MOV	A A A,#03FH rolling_ptr,A	; wrap back round to 0 if >64 ; move value held in ACC back to the rolling pointer
MOV INC ANL MOV SETB	A A A,#03FH rolling_ptr,A T0	
MOV INC INC ANL MOV	A A A,#03FH rolling_ptr,A	; move value held in ACC back to the rolling pointer



## **TLV5606** 2.7-V TO 5.5-V LOW POWER 10-BIT DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN SLAS259B – DECEMBER 1999 – REVISED APRIL 2004

**APPLICATION INFORMATION** 

DS	STACK 10h	; 16 Byte Stack!
;; Main Pr	ogram	
RSEG	MAIN	
start: MOV	SP,#STACK-1 ; :	first set Stack Pointer
CLR MOV MOV MOV	TH0,#0C8H ; ;	set serial port 0 to mode 0 set timer 0 to mode 2 - auto-reload set TH0 for 16.67 kHs interrupts
SETB SETB		set FS = 1 set CSB = 1
SETB SETB		enable timer 0 interrupts enable all interrupts
MOV SETB	rolling_ptr,A TR0	; set rolling pointer to 0 ; start timer 0
always: SJMP RET	always	
; Table o	f 32 sine wave sa	amples used as DAC data
, RSEG sinevals:	SINTBL	
DW	01000H	
DW	0903CH	
DW	05094H	
DW	0305CH	
DW	0B084H	
DW	070C8H	
DW	OFOEOH	
DW	0F066H	
DW	0F038H	
DW DW	0F06CH	
DW	OFOEOH	
DW DW	070C8H	
DW	0B084H	
DW DW	0305CH	
DW DW	05094H	
DW	0903CH	
DW	01000H	
DW	06020H	
DW	0A0E8H	
DW	0C060H	
DW	040F8H	
DW	080B4H	
DW	0009CH	
DW	00050H	
DW	00024H	
DW	00050H	
DW	0009CH	
DW	080B4H	
DW	040F8H	
DW	0C060H	
DW	0A0E8H	
DW	06020H	
END		



SLAS259B - DECEMBER 1999 - REVISED APRIL 2004

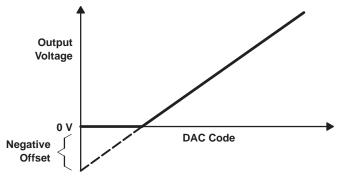
## APPLICATION INFORMATION

### linearity, offset, and gain error using single ended supplies

When an amplifier is operated from a single supply, the voltage offset can still be either positive or negative. With a positive offset, the output voltage changes on the first code change. With a negative offset, the output voltage may not change with the first code, depending on the magnitude of the offset voltage.

The output amplifier attempts to drive the output to a negative voltage. However, because the most negative supply rail is ground, the output cannot drive below ground and clamps the output at 0 V.

The output voltage then remains at zero until the input code value produces a sufficient positive output voltage to overcome the negative offset voltage, resulting in the transfer function shown in Figure 19.





This offset error, not the linearity error, produces this breakpoint. The transfer function would have followed the dotted line if the output buffer could drive below the ground rail.

For a DAC, linearity is measured between zero-input code (all inputs 0) and full-scale code (all inputs 1) after offset and full scale are adjusted out or accounted for in some way. However, single supply operation does not allow for adjustment when the offset is negative due to the breakpoint in the transfer function. So the linearity is measured between full-scale code and the lowest code that produces a positive output voltage.

### power-supply bypassing and ground management

Printed-circuit boards that use separate analog and digital ground planes offer the best system performance. Wire-wrap boards do not perform well and should not be used. The two ground planes should be connected together at the low-impedance power-supply source. The best ground connection may be achieved by connecting the DAC AGND terminal to the system analog ground plane, making sure that analog ground currents are well managed and there are negligible voltage drops across the ground plane.

A 0.1-µF ceramic-capacitor bypass should be connected between V<sub>DD</sub> and AGND and mounted with short leads as close as possible to the device. Use of ferrite beads may further isolate the system analog supply from the digital power supply.

Figure 20 shows the ground plane layout and bypassing technique.

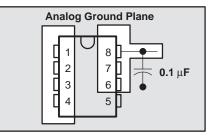


Figure 20. Power-Supply Bypassing



## **APPLICATION INFORMATION**

### definitions of specifications and terminology

#### integral nonlinearity (INL)

The relative accuracy or integral nonlinearity (INL), sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors.

#### differential nonlinearity (DNL)

The differential nonlinearity (DNL), sometimes referred to as differential error, is the difference between the measured and ideal 1 LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code.

#### zero-scale error (E<sub>ZS</sub>)

Zero-scale error is defined as the deviation of the output from 0 V at a digital input value of 0.

#### gain error (E<sub>G</sub>)

Gain error is the error in slope of the DAC transfer function.

#### signal-to-noise ratio + distortion (S/N+D)

S/N+D is the ratio of the rms value of the output signal to the rms sum of all other spectral components below the Nyquist frequency, including harmonics but excluding dc. The value for S/N+D is expressed in decibels.

#### spurious free dynamic range (SFDR)

SFDR is the difference between the rms value of the output signal and the rms value of the largest spurious signal within a specified bandwidth. The value for SFDR is expressed in decibels.

#### total harmonic distortion (THD)

THD is the ratio of the rms sum of the first six harmonic components to the rms value of the fundamental signal and is expressed in decibels.





## PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TLV5606CD	ACTIVE	SOIC	D	8	75	RoHS & Green	(6) NIPDAU	Level-1-260C-UNLIM	0 to 70	5606C	Samples
TLV5606CDGK	ACTIVE	VSSOP	DGK	8	80	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	0 to 70	AGX	Samples
TLV5606CDGKR	ACTIVE	VSSOP	DGK	8	2500	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	0 to 70	AGX	Samples
TLV5606CDR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	5606C	Samples
TLV5606ID	ACTIVE	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	56061	Samples
TLV5606IDG4	ACTIVE	SOIC	D	8	75	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	56061	Samples
TLV5606IDGK	ACTIVE	VSSOP	DGK	8	80	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	AGY	Samples
TLV5606IDGKR	ACTIVE	VSSOP	DGK	8	2500	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	AGY	Samples
TLV5606IDR	ACTIVE	SOIC	D	8	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	56061	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.



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## PACKAGE OPTION ADDENDUM

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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## **PACKAGE MATERIALS INFORMATION**

Texas **NSTRUMENTS** 

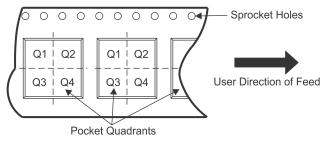
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## **TAPE AND REEL INFORMATION**





### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



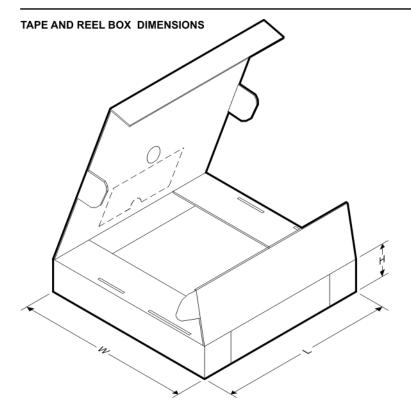
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV5606CDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TLV5606CDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TLV5606IDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TLV5606IDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1



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## PACKAGE MATERIALS INFORMATION

5-Jan-2022



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLV5606CDGKR	VSSOP	DGK	8	2500	350.0	350.0	43.0
TLV5606CDR	SOIC	D	8	2500	350.0	350.0	43.0
TLV5606IDGKR	VSSOP	DGK	8	2500	350.0	350.0	43.0
TLV5606IDR	SOIC	D	8	2500	350.0	350.0	43.0



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## TUBE



* ^ 11	-11		
"All	dimensions	are	nominai

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
TLV5606CD	D	SOIC	8	75	505.46	6.76	3810	4
TLV5606CDGK	DGK	VSSOP	8	80	331.47	6.55	3000	2.88
TLV5606ID	D	SOIC	8	75	505.46	6.76	3810	4
TLV5606IDG4	D	SOIC	8	75	505.46	6.76	3810	4
TLV5606IDGK	DGK	VSSOP	8	80	331.47	6.55	3000	2.88

## D0008A



## **PACKAGE OUTLINE**

## SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



#### NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.

- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 [0.15] per side.
- 4. This dimension does not include interlead flash.
- 5. Reference JEDEC registration MS-012, variation AA.



## D0008A

## **EXAMPLE BOARD LAYOUT**

## SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



## D0008A

## **EXAMPLE STENCIL DESIGN**

## SOIC - 1.75 mm max height

SMALL OUTLINE INTEGRATED CIRCUIT



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

9. Board assembly site may have different recommendations for stencil design.



DGK (S-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.

- D Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- E. Falls within JEDEC MO-187 variation AA, except interlead flash.



## DGK (S-PDSO-G8)

## PLASTIC SMALL OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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